

800V Super-Junction Power MOSFET

RoHS

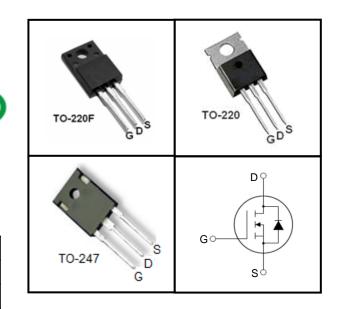
FEATURES

- Very low FOM $R_{DS(on)} \times Q_g$
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)

Device Marking and Package Information				
Device Package Marking				
TPA80R250A	TO-220F	80R250A		
TPP80R250A	TO-220	80R250A		
TPW80R250A	TO-247	80R250A		



Absolute Maximum Ratings $T_c = 25^{\circ}C$, unless otherwise noted					
Parameter		Symbol	Value		
			TO-220F	TO-220,TO-247	Unit
Drain-Source Voltage (V _{GS} =	0V)	V _{DSS}	800		V
$T_c = 25^{\circ}C$			18		A
Continuous Drain Current $T_c = 100^{\circ}C$		I _D	10.8		
Pulsed Drain Current (note1)		I _{DM}	54		А
Gate-Source Voltage		V _{GSS}	±30		V
Single Pulse Avalanche Energy (note2)		E _{AS}	280		mJ
Avalanche Current (note1)		I _{AR}	7.5		А
Repetitive Avalanche Energy (note1)		E _{AR}	0.5		mJ
Power Dissipation ($T_c = 25^{\circ}C$)		P _D	34	240	W
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150		°C

Thermal Resistance				
Parameter	Symbol	Va	Unit	
	TO-220F			TO-220,TO-247
Thermal Resistance, Junction-to-Case	R _{thJC}	3.67	0.52	00000
Thermal Resistance, Junction-to-Ambient	R _{thJA}	80	62	°C/W

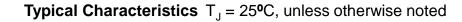


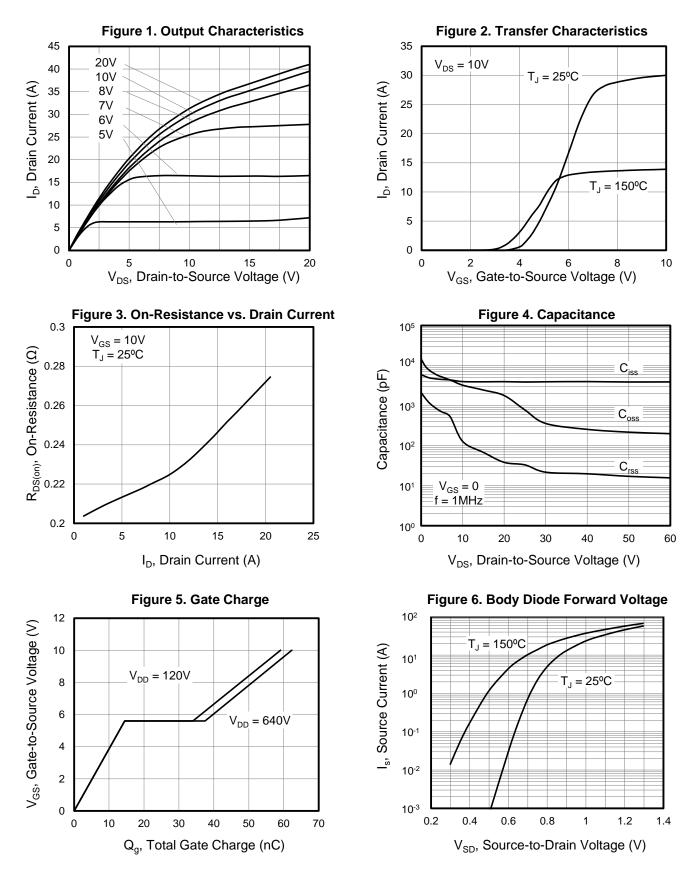
				Value			
Parameter	Symbol Test Conditions		Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = 250 \mu A$	800			V	
	I _{DSS}	$V_{DS} = 800V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	1 100 μΑ	
Zero Gate Voltage Drain Current		$V_{DS} = 800V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			100		
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30 V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.5		4.5	V	
Drain-Source On-Resistance (Note3)	$R_{DS(on)}$	V _{GS} = 10V, I _D = 9A		0.24	0.28	Ω	
Forward Transconductance (Note3)	g _{fs}	V _{DS} = 10V, I _D = 9A		10		S	
Dynamic		•					
Input Capacitance	C _{iss}			3871		pF	
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 50V,$		217			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		17.1			
Total Gate Charge	Q _g			62.3		nC	
Gate-Source Charge	Q _{gs}	$V_{DD} = 640V, I_{D} = 18A, V_{GS} = 10V$		14.5			
Gate-Drain Charge	Q_{gd}			23			
Turn-on Delay Time	t _{d(on)}			49			
Turn-on Rise Time	t _r	V _{DD} = 400V, I _D = 9A,		42.6			
Turn-off Delay Time	t _{d(off)}	$R_{G} = 25\Omega$		166		ns	
Turn-off Fall Time	t _f			13			
Drain-Source Body Diode Characteris	stics						
Continuous Body Diode Current	I _S	T 0500			18	Δ	
Pulsed Diode Forward Current	I _{SM}	T _C = 25°C			54	A	
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}C, I_{SD} = 18A, V_{GS} = 0V$		0.9	1.2	V	
Reverse Recovery Time	t _{rr}			400		ns	
Reverse Recovery Charge	Q _{rr}	$V_R = 400V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		4		μC	
Peak Reverse Recovery Current	l _{rrm}			20		А	

Notes

- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2. I_{AS} = 7.5A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25°C
- 3. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 1%

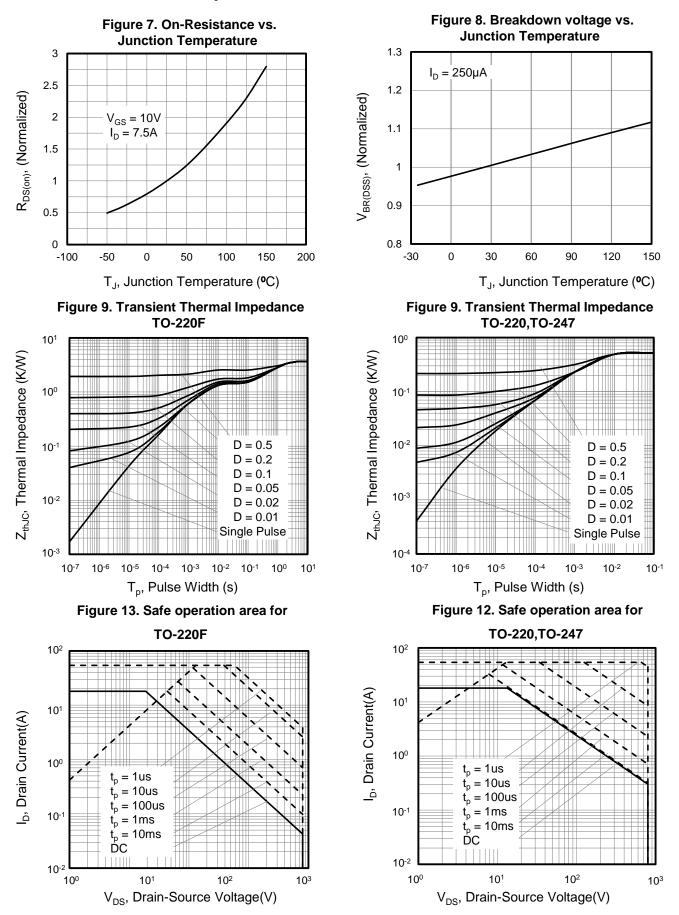






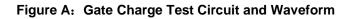
E

Wuxi Unigroup Microelectronics Company



Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted





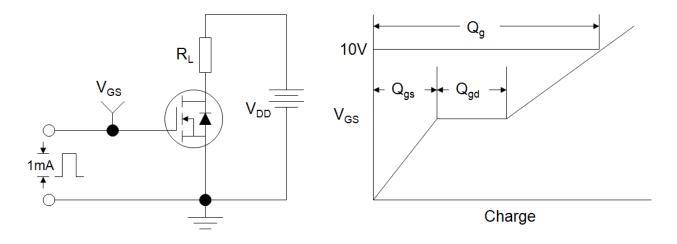


Figure B: Resistive Switching Test Circuit and Waveform

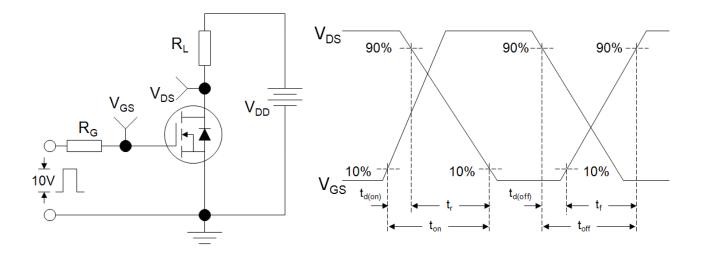
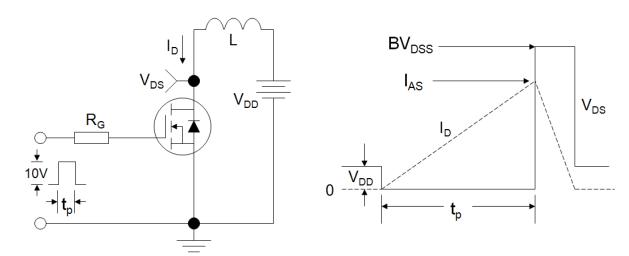
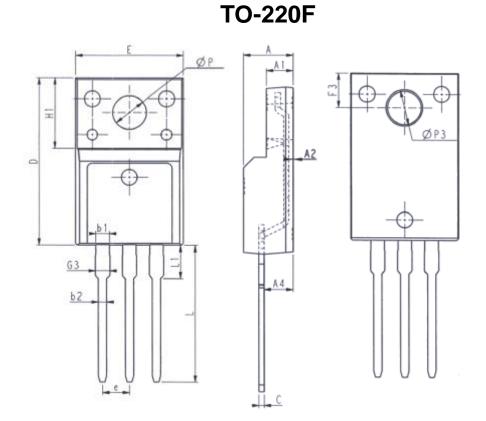


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



E

Wuxi Unigroup Microelectronics Company



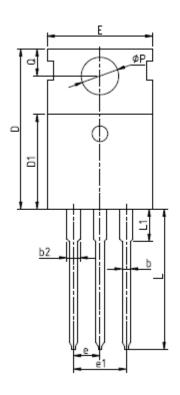
	MM			
SYMBOL	MIN	NOM	MAX	
E	9.96	10.16	10.36	
A	4.50	4.70	4.90	
A1	2.34	2.54	2.74	
A2	0.30	0.45	0.60	
A4	2.56	2.76	2.96	
с	0.40	0.50	0.65	
c1	1.20	1.30	1.35	
D	15.57	15.87	16.17	
H1		6. 70REF		
е		2.54BSC		
L	12.68	12.98	13.28	
L1	2, 93	3.03	3.13	
ΦP	3.03	3.18	3.38	
Φ P 3	3.15	3.45	3.65	
F3	3.15	3.30	3.45	
G3	1.25	1.35	1.55	
b1	1.18	1.28	1.43	
b2	0.70	0.80	0.95	

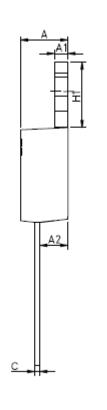
V2.0

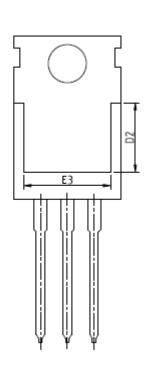
E

Wuxi Unigroup Microelectronics Company

TO-220



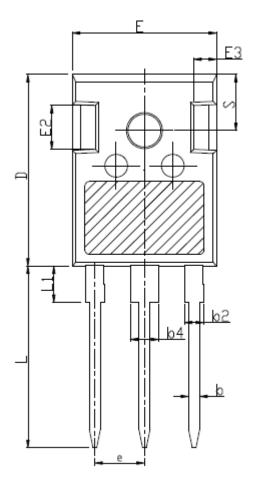


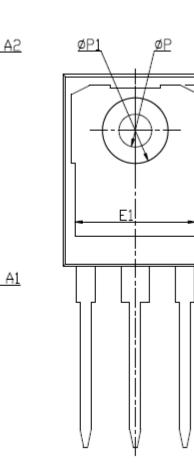


SYMBOL	MIN	NOM	MAX
Α	4.37	4.57	4.70
A1	1.25	1.30	1.40
A2	2.20	2.40	2.60
b	0.70	0.80	0.95
b2	1.17	1.27	1.47
с	0.45	0,50	0.60
D	15.10	15.60	16.10
D1	8,80	9,10	9.40
D2	5, 50	-	-
Е	9.70	10.00	10.30
E3	7.00	-	-
е		2.54	BSC
e1		5,08	BSC
H1	6.25	6, 50	6.85
L	12.75	13, 50	13.80
L1	-	3.10	3, 40
ΦP	3.40	3,60	3.80
Q	2.60	2.80	3.00



TO-247





Ξ

CAMPOL	mm			
SYMBOL	MIN	NOM	MAX	
A	4.80	5.00	5.20	
A1	2.21	2.41	2.59	
A2	1.85	2.00	2.15	
b	1.11	1.21	1.36	
b2	1.91	2.01	2.21	
b4	2.91	3.01	3.21	
с	0.51	0.61	0.75	
D	20.80	21.00	21.30	
D1	16.25	16.55	16.85	
E	15, 50	15.80	16.10	
E1	13.00	13.30	13.60	
E2	4.80	5.00	5.20	
E3	2.30	2.50	2.70	
е	5.44BSC			
L	19.62	19.92	20.22	
L1	-	-	4.30	
ΦP	3.40	3.60	3.80	
ΦΡ1	-	-	7.30	
S	6. 15BSC			

C



Disclaimer

All product specifications and data are subject to change without notice.

For documents and material available from this datasheet, Wuxi Unigroup does not warrant or assume any legal liability or responsibility for the accuracy, completeness of any product or technology disclosed hereunder.

No license, express or implied, by estoppels or otherwise, to any intellectual property rights is granted by this document or by any conduct of Wuxi Unigroup.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications. Customers using or selling Wuxi Unigroup products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Wuxi Unigroup for any damages arising or resulting from such use or sale.

Wuxi Unigroup disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Wuxi Unigroup's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

Wuxi Unigroup Microelectronics CO., LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.

In the event that any or all Wuxi Unigroup products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.

Information (including circuit diagrams and circuit parameters) herein is for example only. It is not guaranteed for volume production. Wuxi Unigroup believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.